

# Polymer transistors and TFT backplanes

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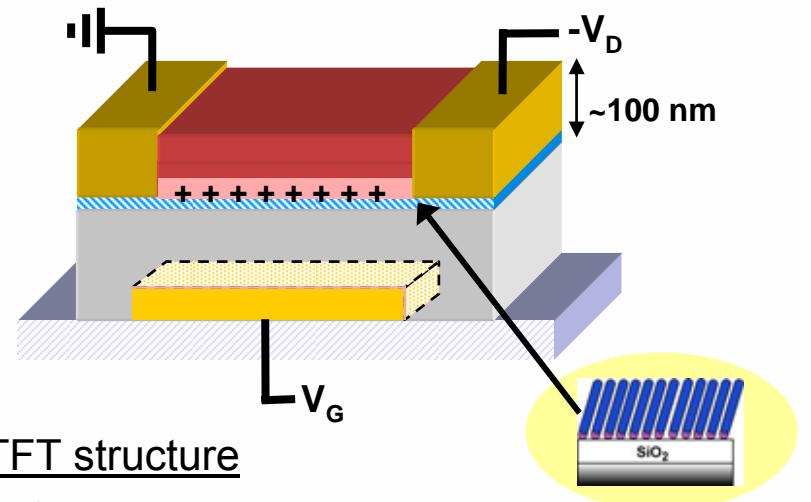
## Acknowledgements

Raj Apte  
Ana Arias  
Michael Chabinyo  
Jürgen Daniel  
Fred Endicott  
Julia Greer  
Rene Lujan  
Brent Krusor  
John Northrup  
Steve Ready  
Alberto Salleo  
Veronica Sholin  
William Wong

**Funding; NIST ATP**

# Outline

- Polymer TFTs on glass and flex
  - Materials
  - TFTs and backplanes
  - Plastic substrates and mechanical stress
- TFT mobility
  - Physical structure of films
  - Interfaces
  - Electronic structure
  - Transport models
- Transistor Lifetime
  - Bias stress effects
  - Chemical effects and encapsulation



Typical TFT structure

Bottom gate

Coplanar source/drain

Polymer deposited on SAM

SAM (~ 20 Å thick)

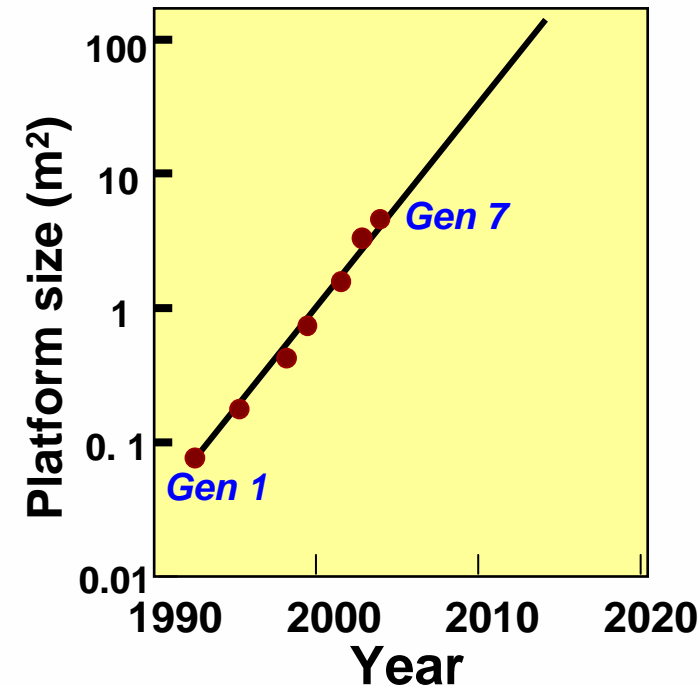
# Motivation

- How many more generations before the cost outweighs the benefits?

## Alternative technology

- Lower cost equipment → printing
- Less material use → additive processes
- R2R processing → flexible substrates
- New functionality → conformable, rollable, lightweight.....

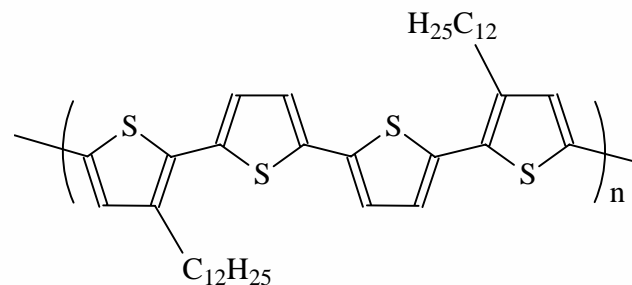
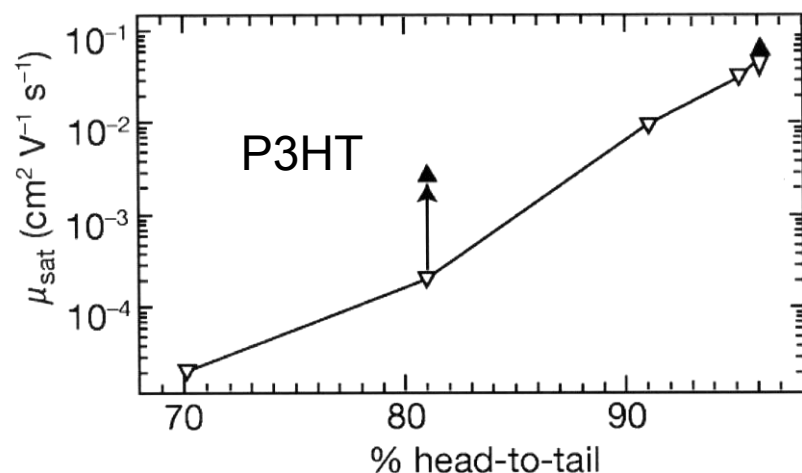
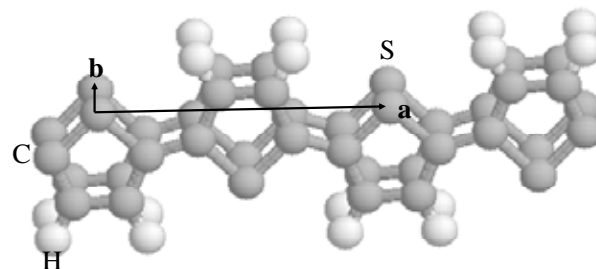
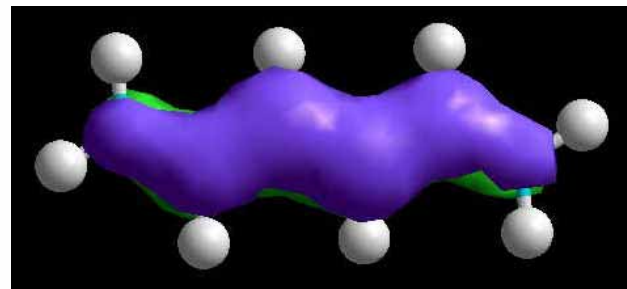
→ Jet-printing  
→ Printable materials  
→ Flexible substrates



Applications, LCD, OLED,  
e-paper, signage etc

# Soluble polymer semiconductors

- Conjugated
  - Mostly p-type conduction, 1.5-2 eV band gap
- Alkyl side groups added for solubility
  - Regioregular
  - Polythiophene, PQT-12
- Structural order required for high mobility
  - $\pi$  stacked lamella structure

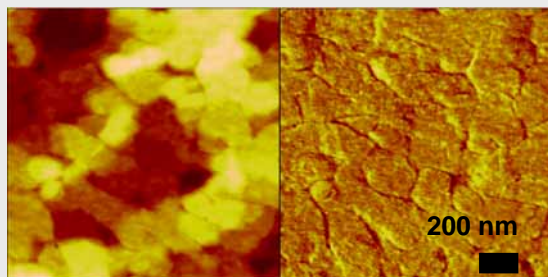


PQT;

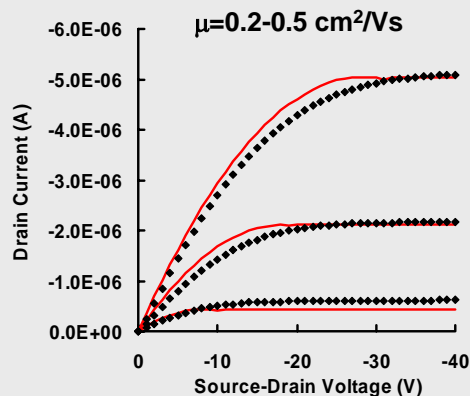
*Ong et al. JACS, 126, 3378 (2004)*

# Polythiophene TFTs

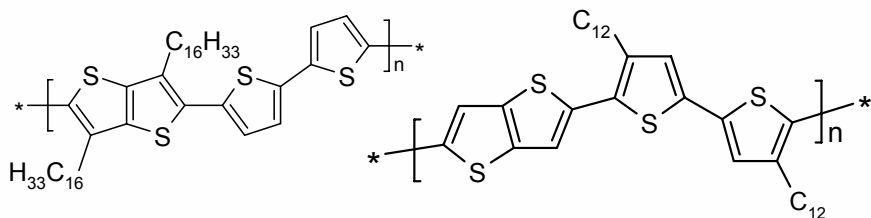
Merck material 180C anneal



topography phase

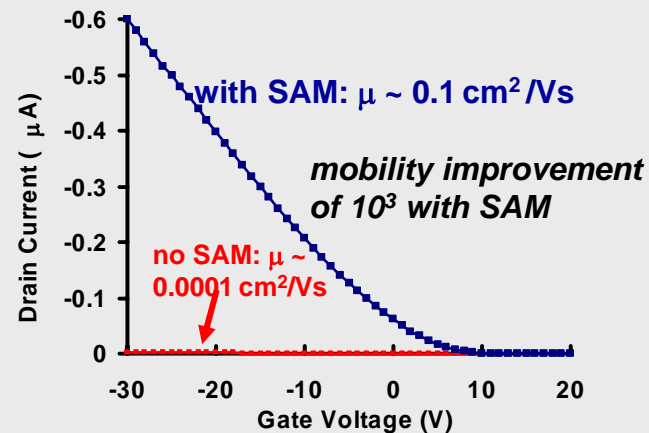
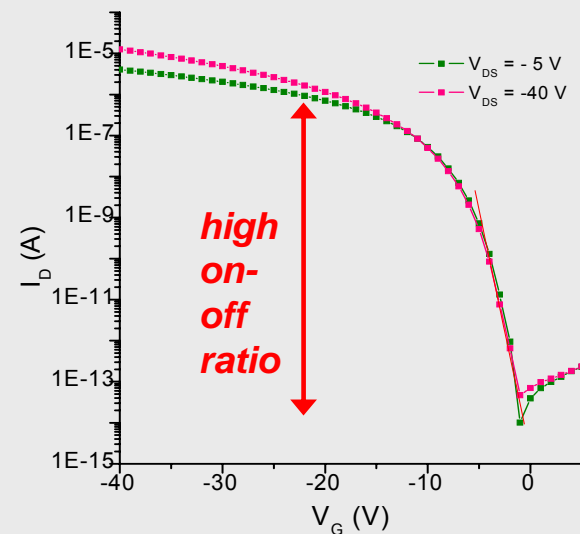


I. McCulloch, et. al. *Nat Mat.* 2006



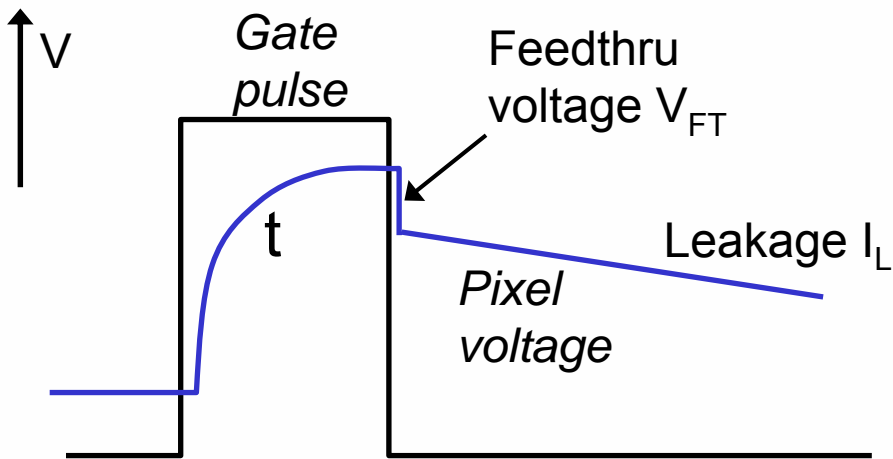
## PQT

- Mobility 0.03-0.15 cm<sup>2</sup>/Vs
  - Best on thermal oxide
  - Lower on large area dielectric



# TFT Backplanes

- Capacitive displays; LCD, reflective
- Current drive; OLED



$$V_{FT} = V_G C_{\text{parasit}} / C_{\text{pix}}$$

$$t = R_{\text{TFT}} \cdot C_{\text{pixel}}$$

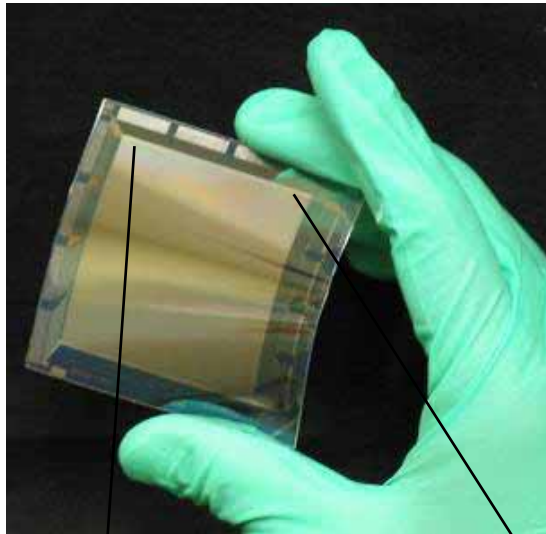
$$dV/dt = I_L / C_{\text{pixel}}$$

Printing  $\rightarrow$  large  $C_{\text{parasit}}$   $\rightarrow$  Large  $C_{\text{pixel}}$   $\rightarrow$  high mobility

# A-Si arrays on flex

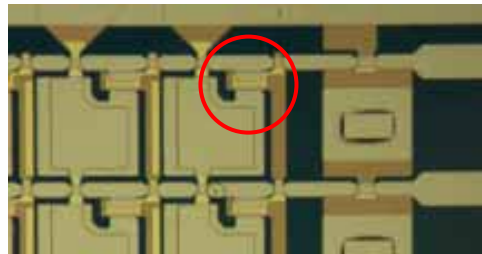
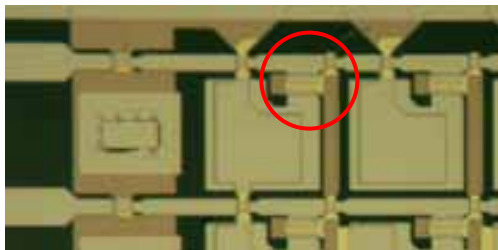
Printed polymer array on flex

512x512 a-Si array on PEN

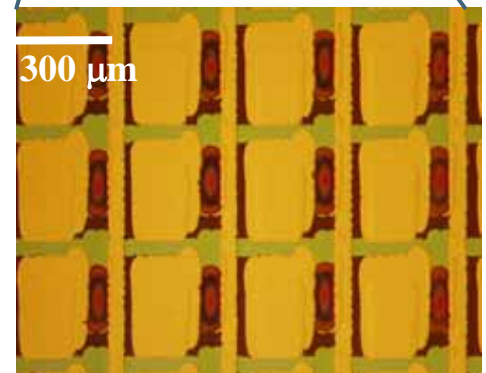
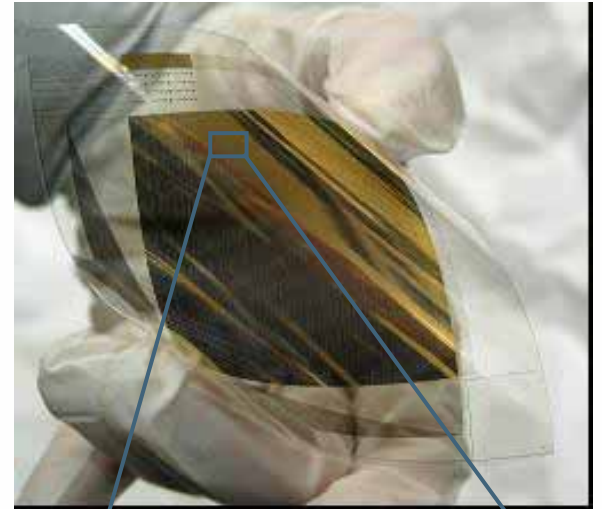


Upper left corner

Upper right corner



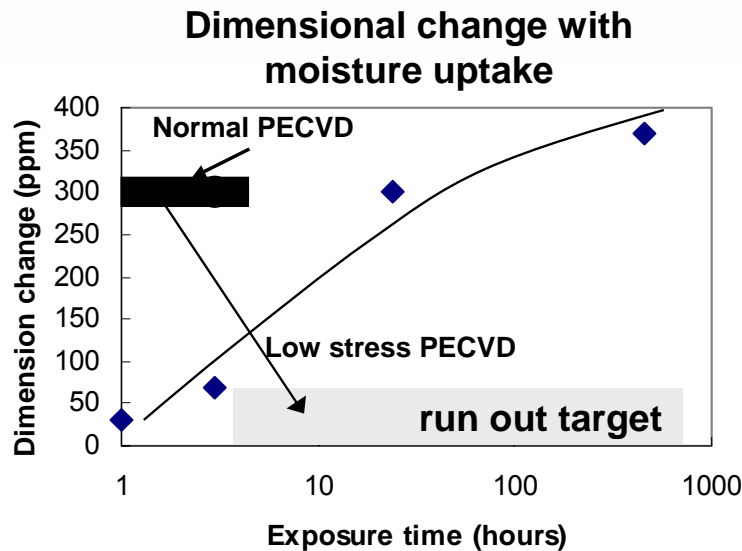
100  $\mu\text{m}$



# Plastic substrates: Control of run-out

Dimensional stability of plastics is much poorer than glass or steel

- Run-out is induced by
  - mechanical stress in deposited film
    - » Thin film deposition
    - » Thermal expansion mismatch
  - Moisture uptake



Elastic modulus  $Y$ :

Glass ~100 GPa

Steel ~200 GPa

Plastic ~1-5 GPa

Run-out:

$$\varepsilon_S = \varepsilon_F \frac{Y_F t_F}{Y_S t_S + Y_F t_F}$$

Glass  $Y_S t_S \gg Y_F t_F$

$$\varepsilon_S = \varepsilon_F \frac{Y_F t_F}{Y_S t_S} \ll \varepsilon_F$$

Plastic;  $Y_S t_S \sim Y_F t_F$

$$\varepsilon_S \approx \varepsilon_F$$

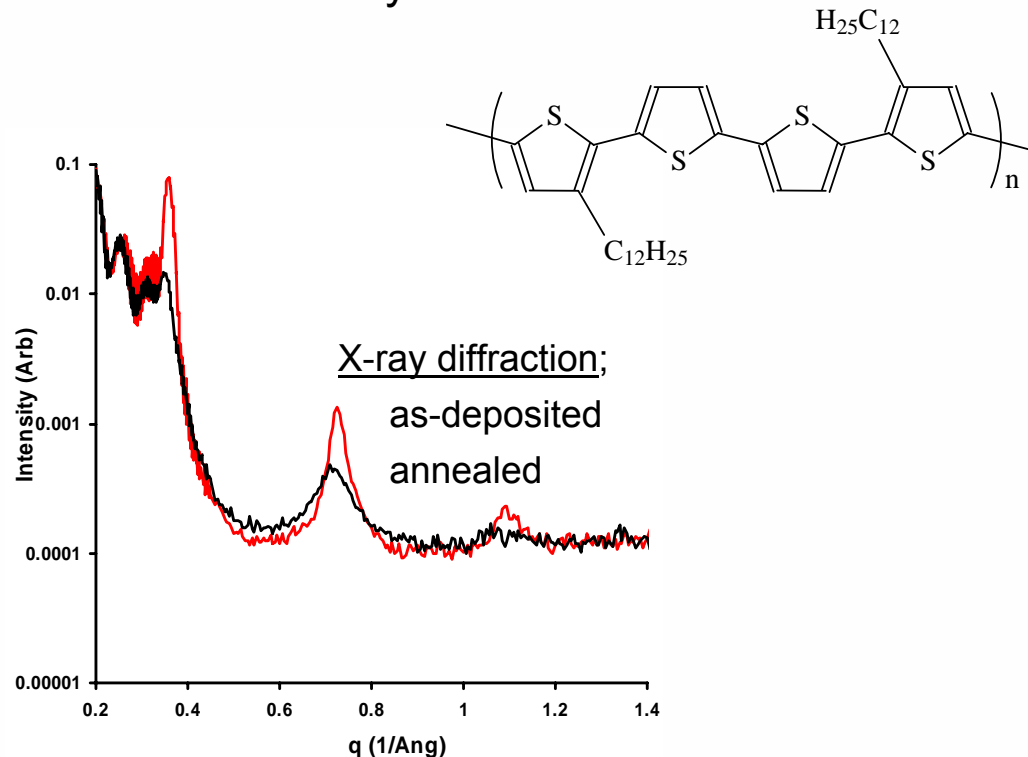
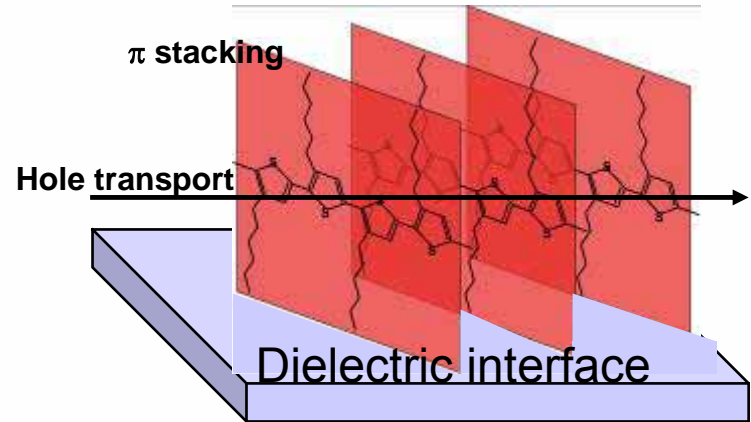


# TFT mobility

- Physical structure of films
  - Dielectric interfaces
- Electronic structure
  - Density of states
- Transport models

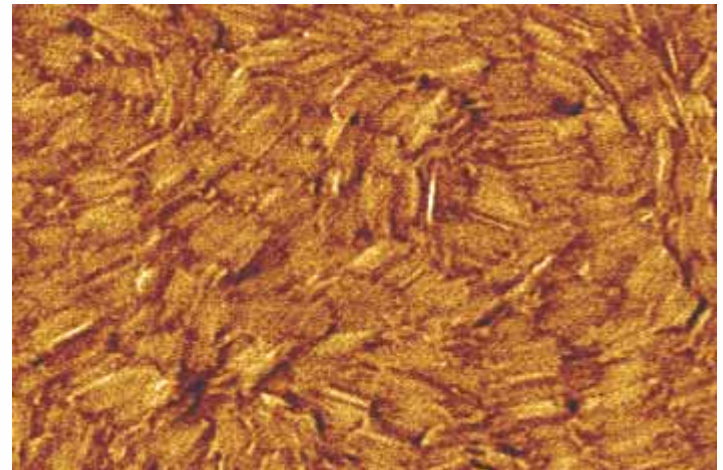
# High mobility polymer semiconductors

- $\pi$  stacked lamella structure
- Highly oriented crystalline film
  - 10-100 nm ordered regions
  - Separated by amorphous material
- Transport in  $\sim 1$  molecular layer
  - 2-d density of states



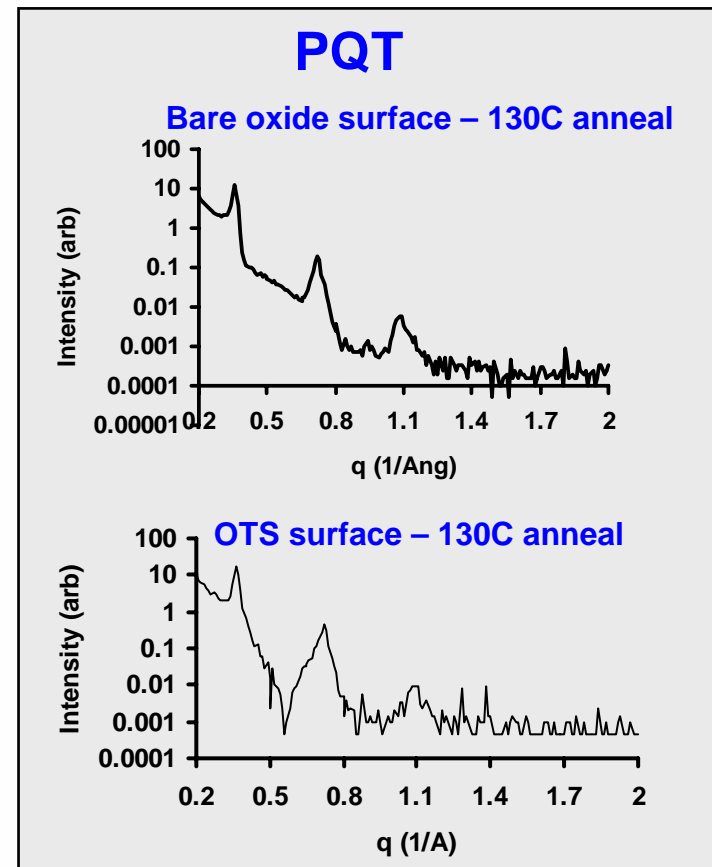
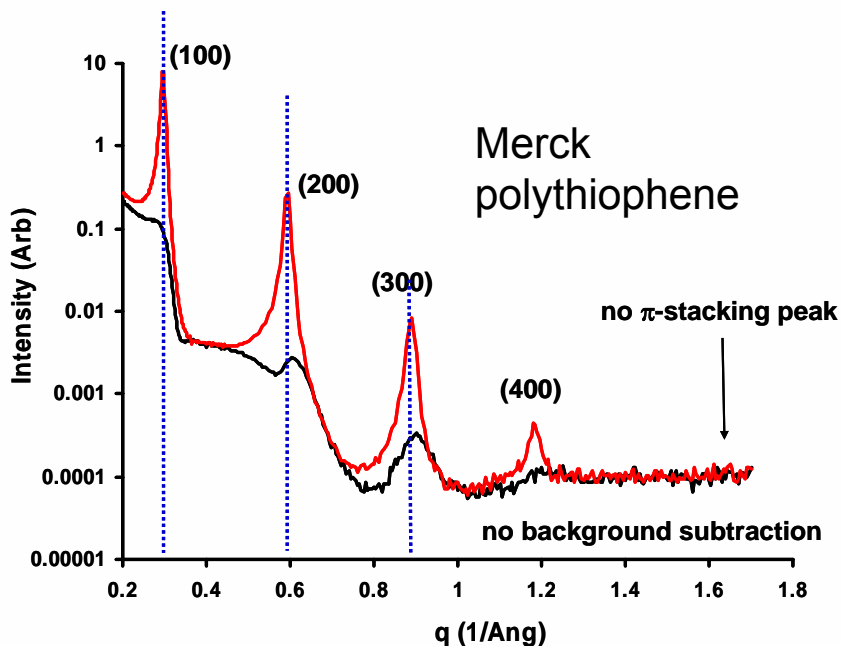
*X-ray measurement of  
ordered structure*

*AFM image of PQT*



# X-ray diffraction data

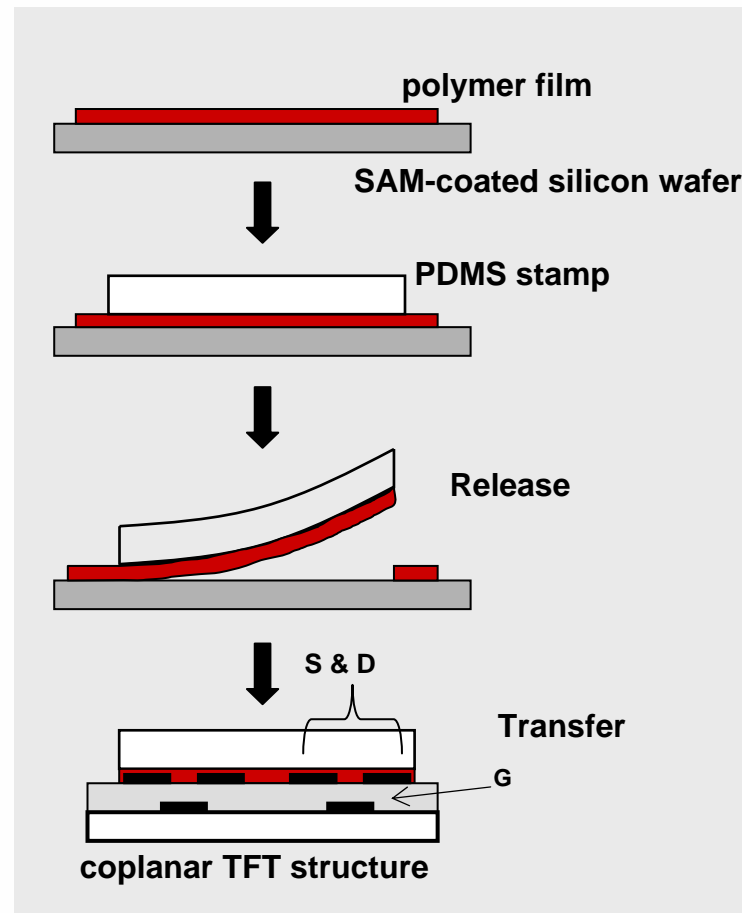
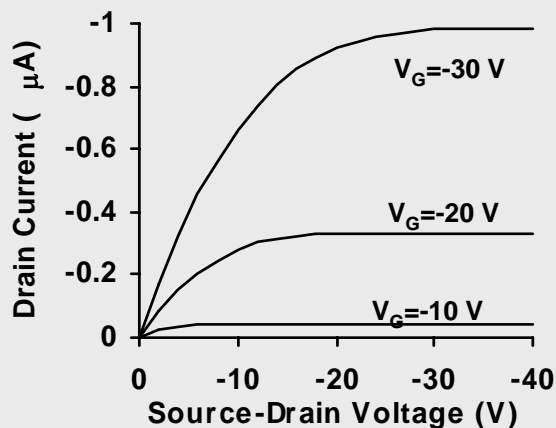
- Lamellar ordering and (hopefully) crystal structure
  - Highly ordered material is best (?)
- PQT out of plane x-ray has similar scattering for OTS and bare Si, but mobility is 1000x different
  - What happens at the interface?



# Studying interfaces by delamination

- Polymer layer can be transferred from one surface to another
- Transfer from SAM-coated surface to TFT structure
  - comparable TFT performance as spin-coated films
- Test role of surface to determine structure
  - Transfer then anneal

TFT characteristics of transferred TFT

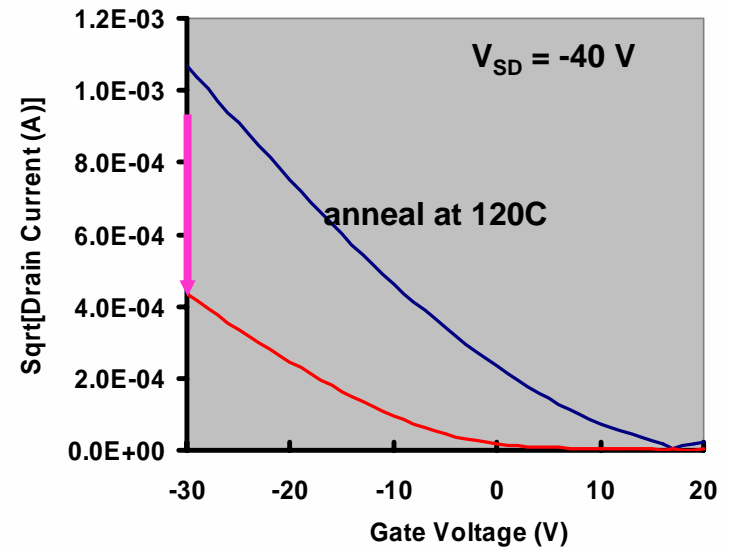


Chabinyk et al. JACS, 126, 13928, 2004.

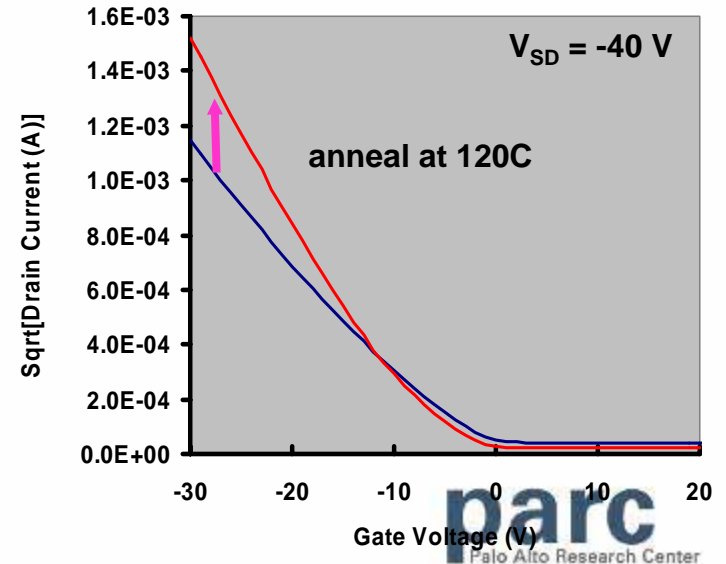
# Transferred TFTs

- Transfer to bare oxide dielectric
  - Starting mobility  $\sim 0.015\text{--}0.03\text{ cm}^2/\text{Vs}$
  - mobility **decreases** on annealing
- Transfer to oxide + OTS
  - mobility **increases** on annealing
- The polymer surface structure is  $\sim$ stable at room temperature
  - 120C anneal allows structural change
- Structure controlled by energetics, not kinetics
  - The equilibrium structure depends on the surface hydrophobicity

Transfer to bare oxide/nitride

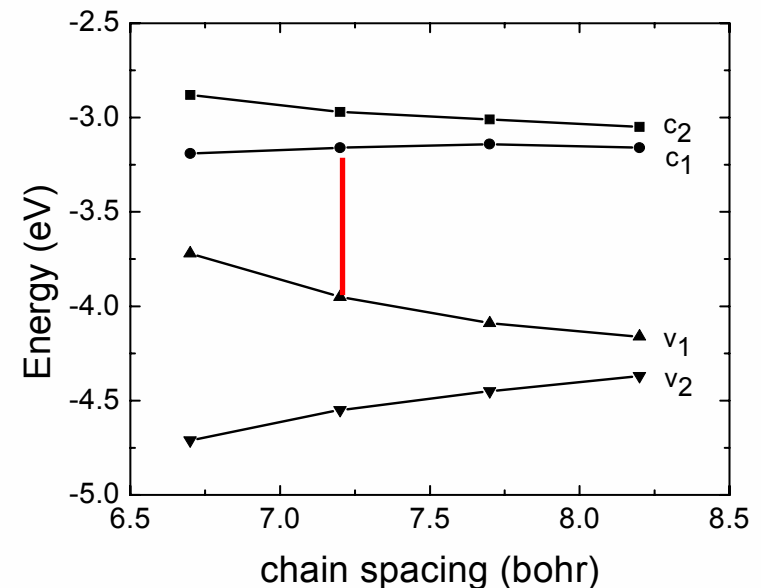
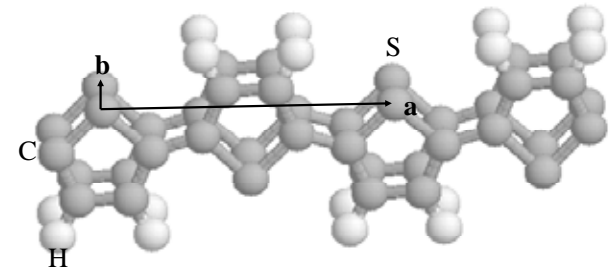


Transfer to OTS8-oxide/nitride



# Electronic structure calculations

- LDA calculations of crystalline structure
  - no electron-phonon interaction
- $\pi$ - $\pi$  interaction widens bands
- Valence band shifts w.r.t. amorphous material by  $\sim 0.3$  eV
- 2-dimensional DOS
  - $2 \times 10^{14} \text{ cm}^{-2} \text{ eV}^{-1}$
- Estimate of RT mobility
  - Acoustic phonon scattering
  - $\mu_0 \sim 10 \text{ cm}^2/\text{Vs}$  in  $\pi$  direction

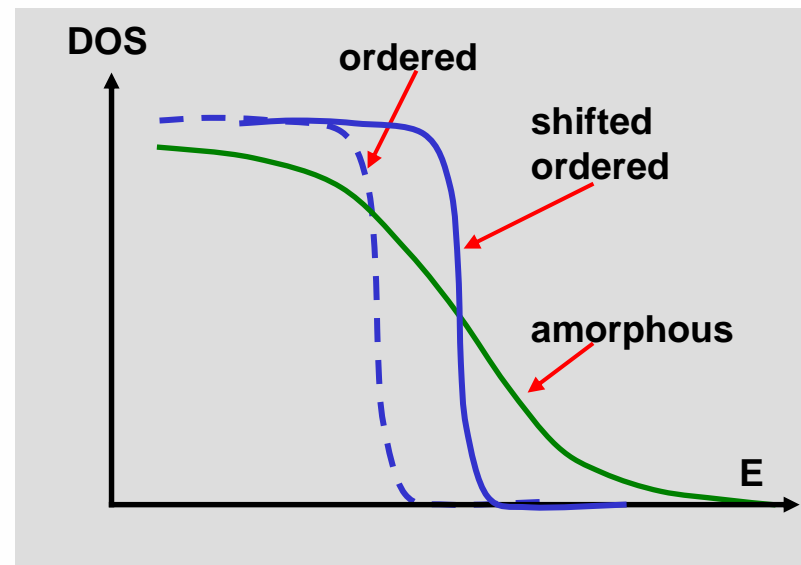
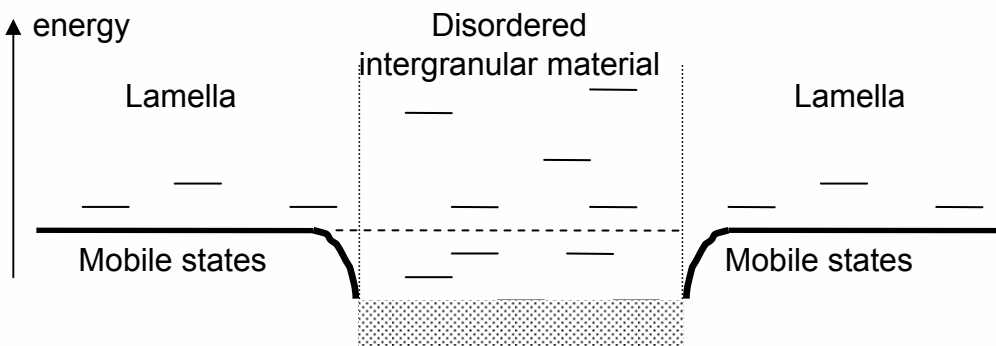
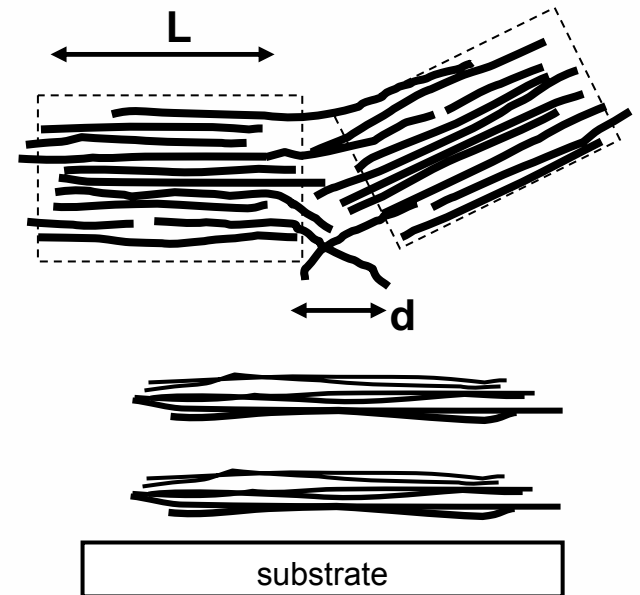


Change of band edges with chain spacing

$$\mu = \frac{2\pi\hbar^4 Be}{\varepsilon_{ac}^2 (3kT)^{3/2} (m^*)^{5/2}}$$

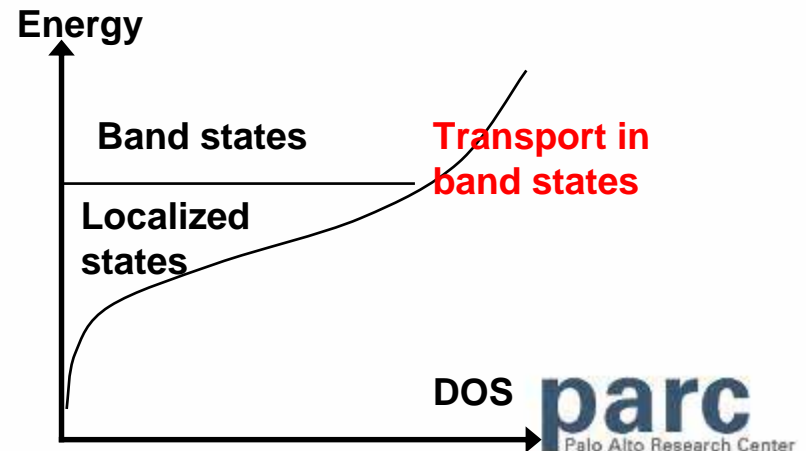
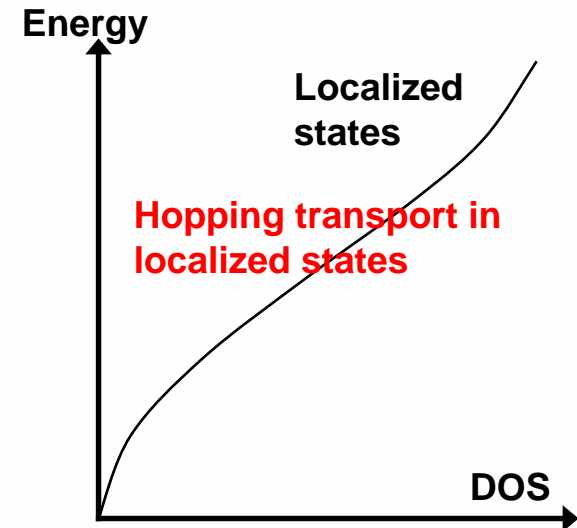
# DOS for mixed phase material

- Amorphous fraction =  $2d/L$ 
  - At least 10-20%
- Shift of band edge
  - $\sim 0.3$  eV
  - barrier to the amorphous region



# Transport processes

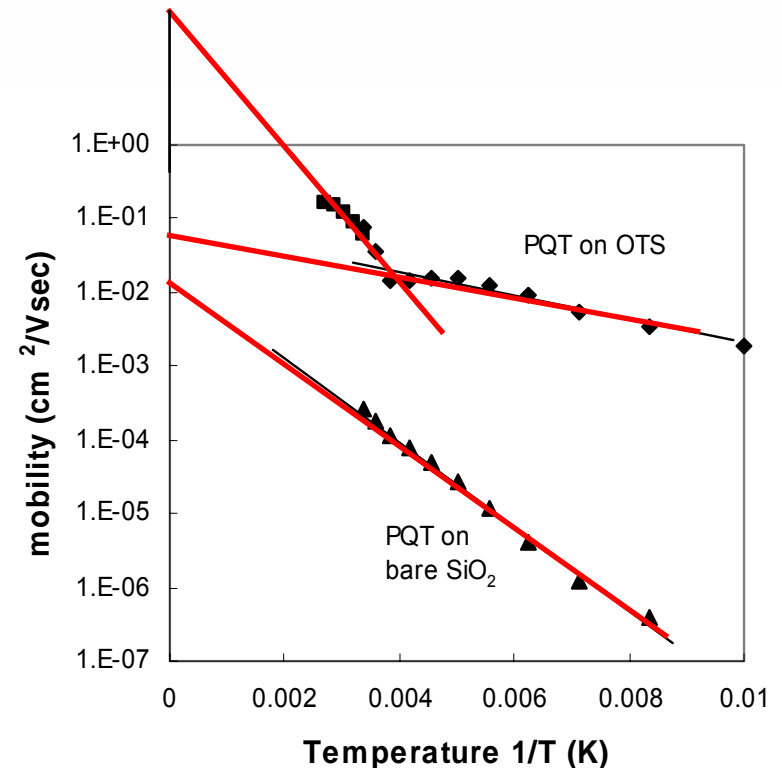
- Amorphous polymers
  - Hopping in broad band of localized states
  - Low mobility
- Single crystal organics
  - Band transport
- Polycrystalline polymers
  - Mixture of amorphous and crystalline
  - What role does each have in the transport?
  - How do you know?





# Transport in PQT

- Thermally activated transport
- High mobility material has much higher prefactor ( $\sim 500 \text{ cm}^2/\text{Vs}$ )
 
$$\mu = \mu_{PRE} \exp[E_T/kT].$$
  - Implies high band mobility and high DOS
- Low mobility material has low prefactor
  - Implies a different transport process

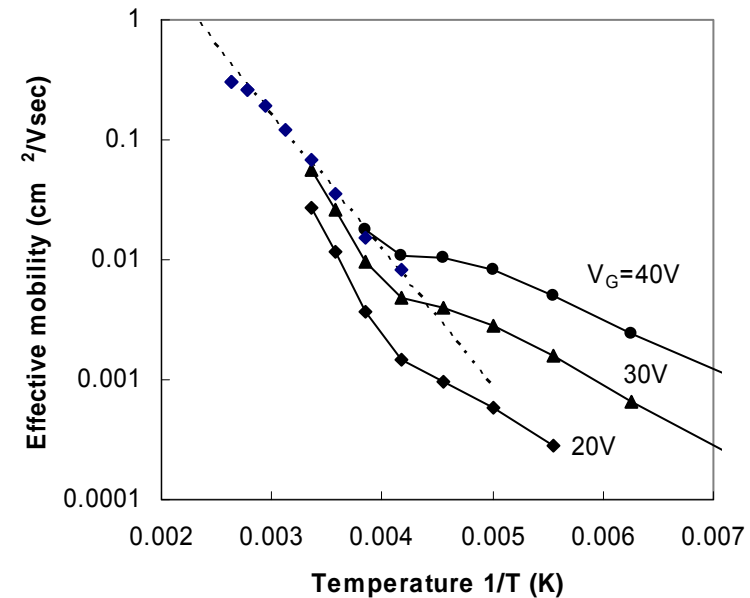


$$\mu_{PRE} = \frac{\mu_0 N_V kT}{n_T} \exp(-\gamma_T / k)$$

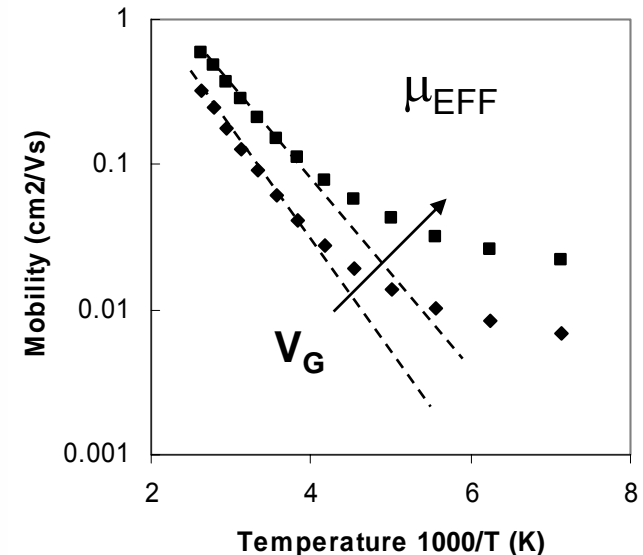
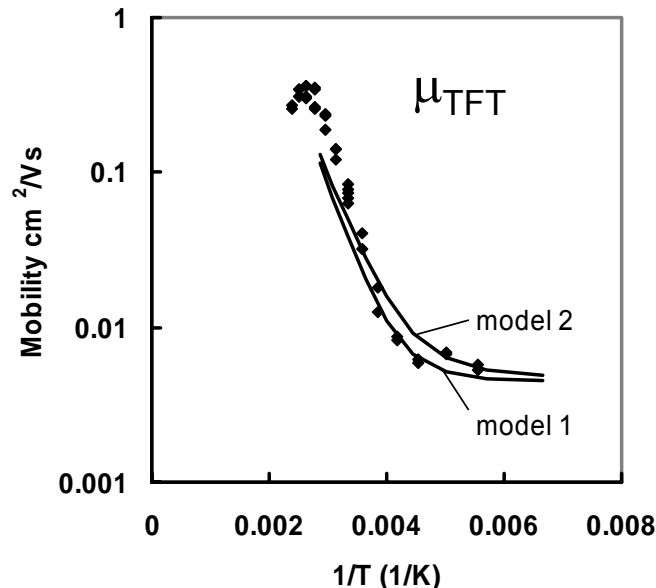
Statistical shift

# Transport model calculations

- Model can fit the mobility and T-dependence
  - reasonable value of prefactor
- Change of slope explained by transport in amorphous regions



## Calculated versus measured conduction data

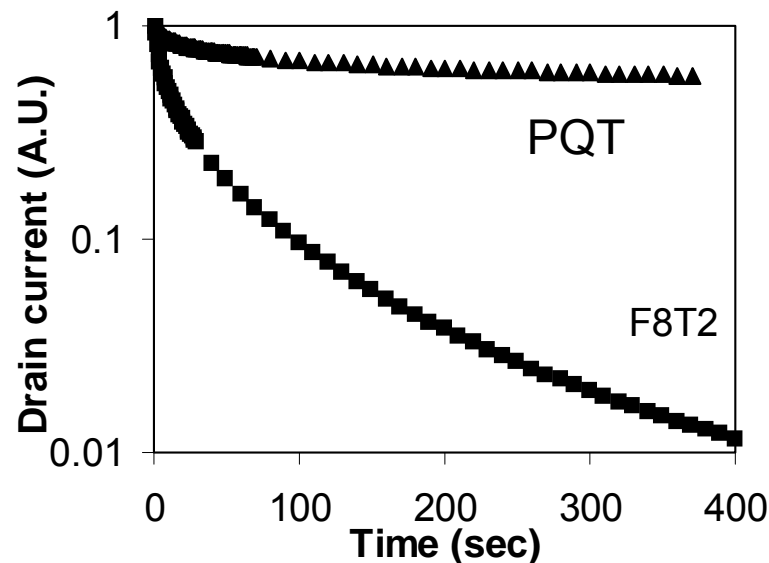
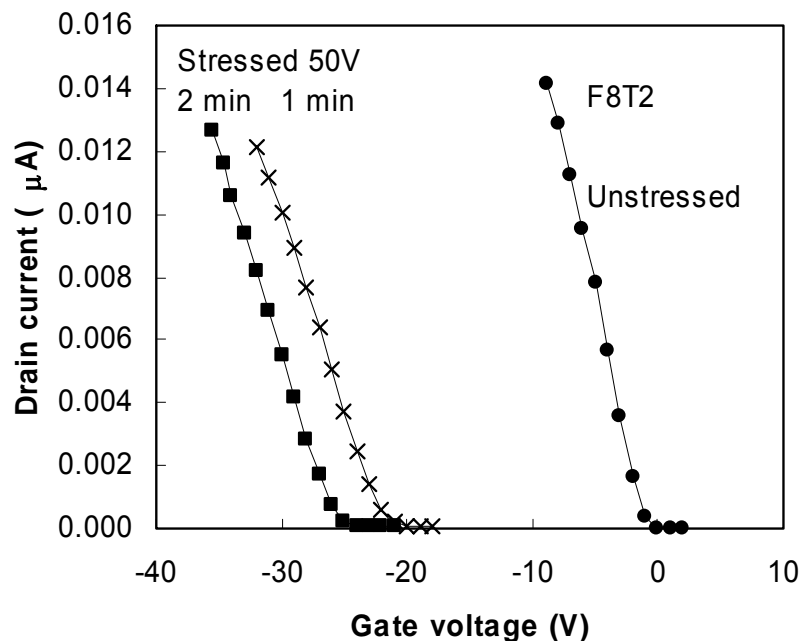


# Lifetime

- Bias stress
- Chemical

# Bias-stress effects

- Threshold voltage shift; no change in mobility
  - Slow charge trapping
- Effect in the polymer, rather than the SAM or the dielectric
  - Depends on the polymer
  - Independent of dielectric

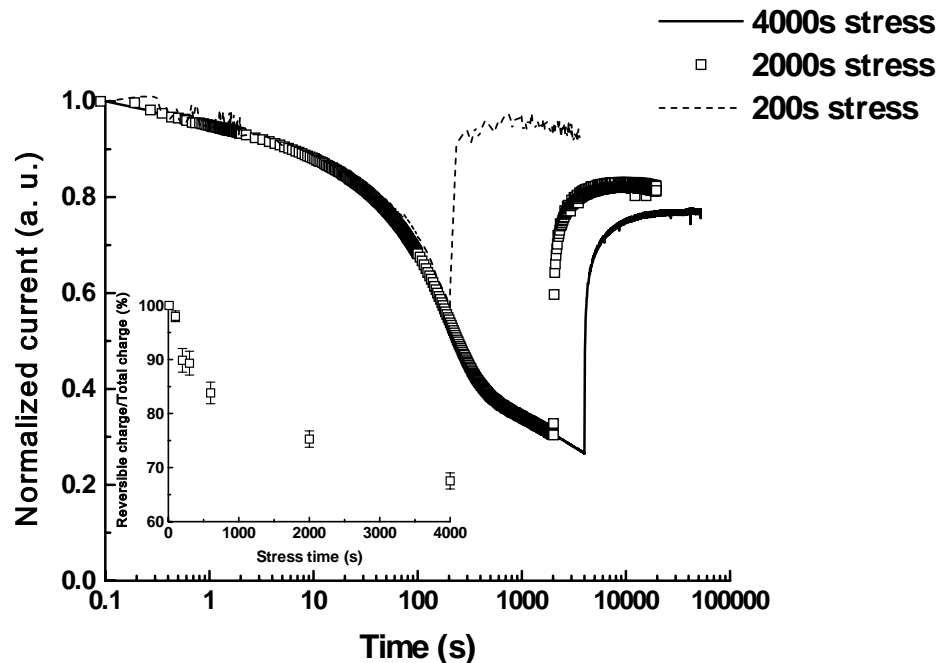
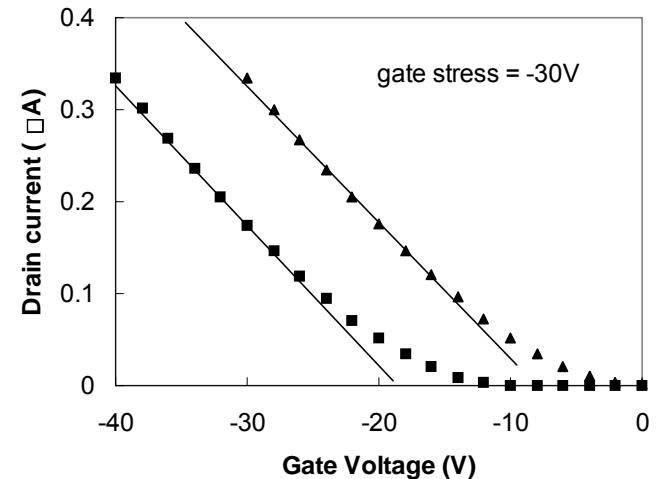


PQT: initial stress reverses quickly  
F8T2; stable stress, reversed by  
-illumination  
-annealing

# Bias stress in polymer TFTs

## Fast and slow stress effects in PQT

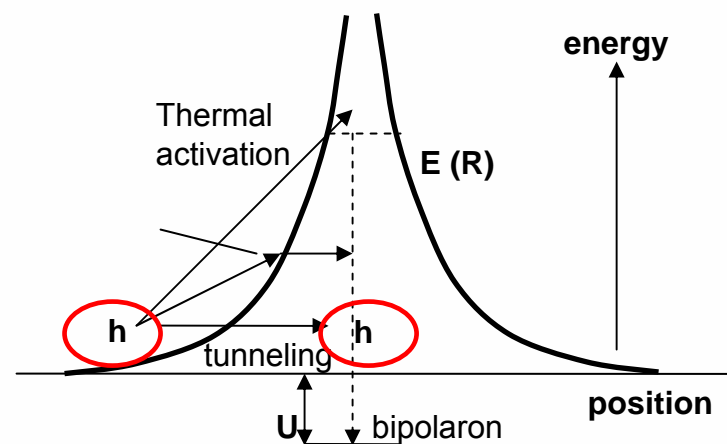
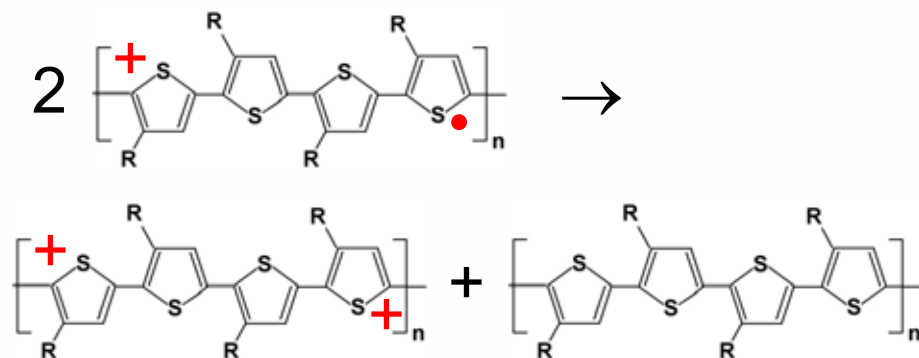
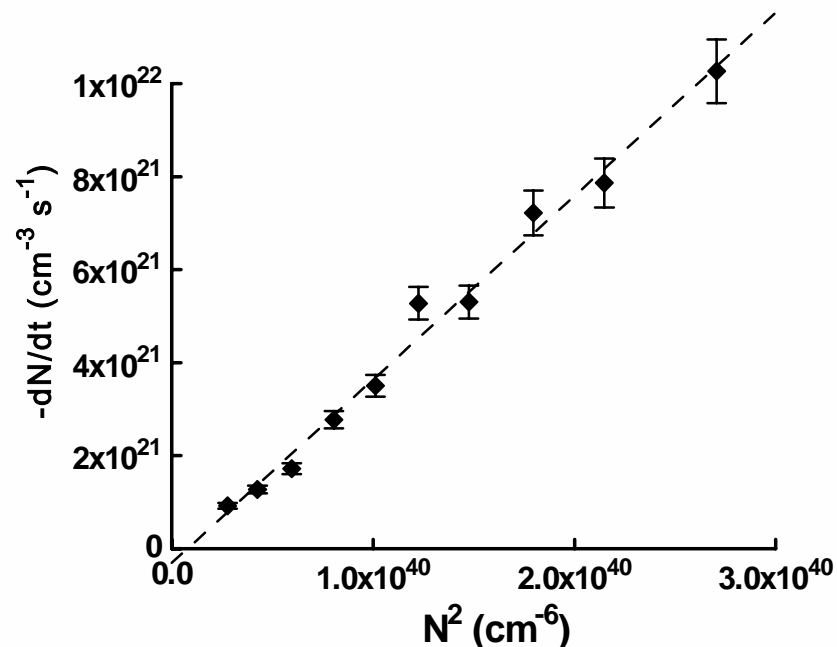
- Threshold voltage shift
- Fast process;
  - Stress occurs in a few seconds
  - Reverses equally quickly
  - Not important for TFT arrays
- Slow process
  - Dominates after 100s-1000s sec
  - Reverses slowly



# Bias-stress effects

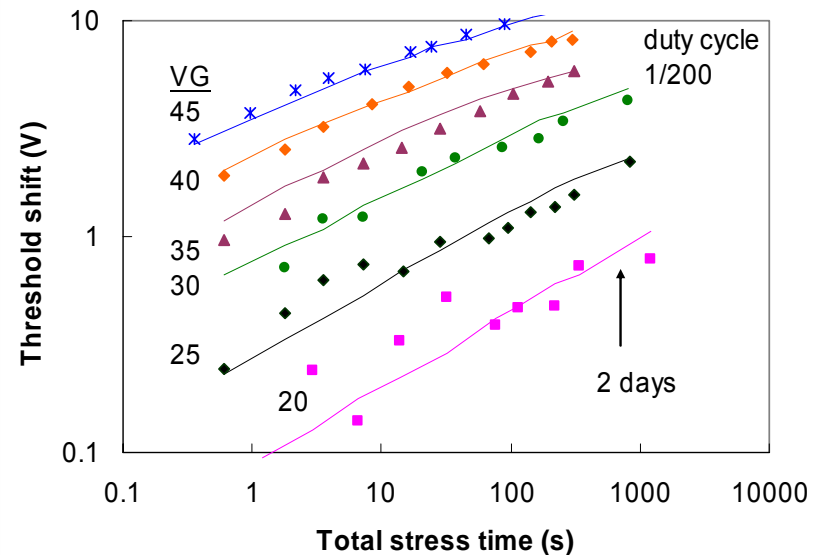
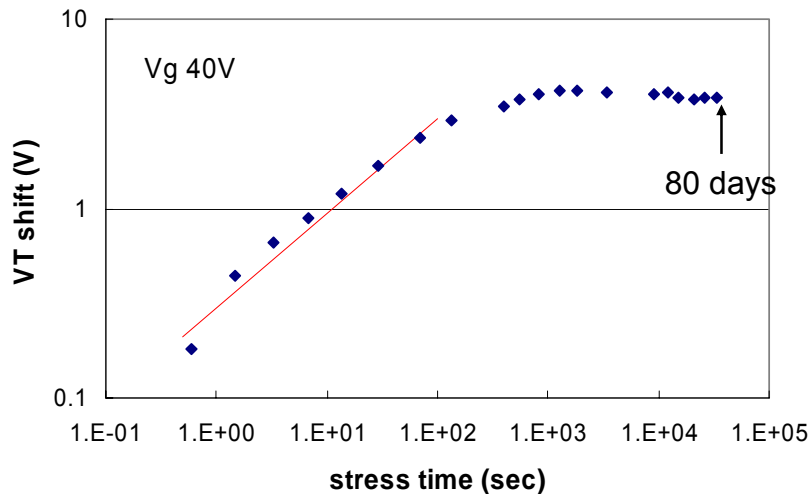
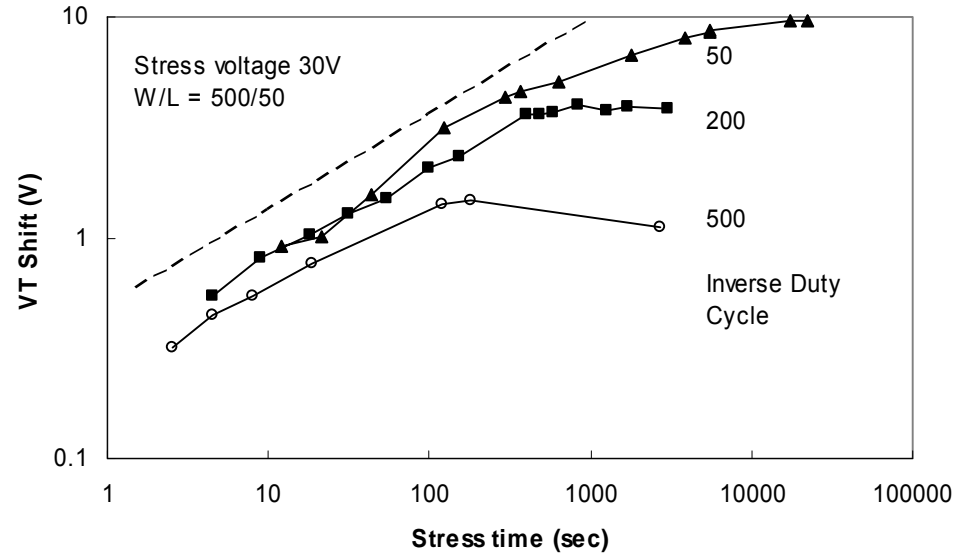
- Second order trapping kinetics  

$$dN_H/dt = k N_H^2$$
- Pairs of holes interact and trap
  - Bipolaron ( $h + h \leftrightarrow BP$ )
  - Stabilized by structural relaxation
- Trapping rate is slow because of Coulomb repulsion
  - Tunnelling mechanism?



# Slow bias stress in PQT

- At low duty cycle
  - Slow process only
  - $V_T$  shift increases as power law  $t^\alpha$ ,  $\alpha = 0.3-0.5$
  - $V_T$  shift saturates due to slow recovery
- Recovery time constant  $\sim 100$  hours at 300K



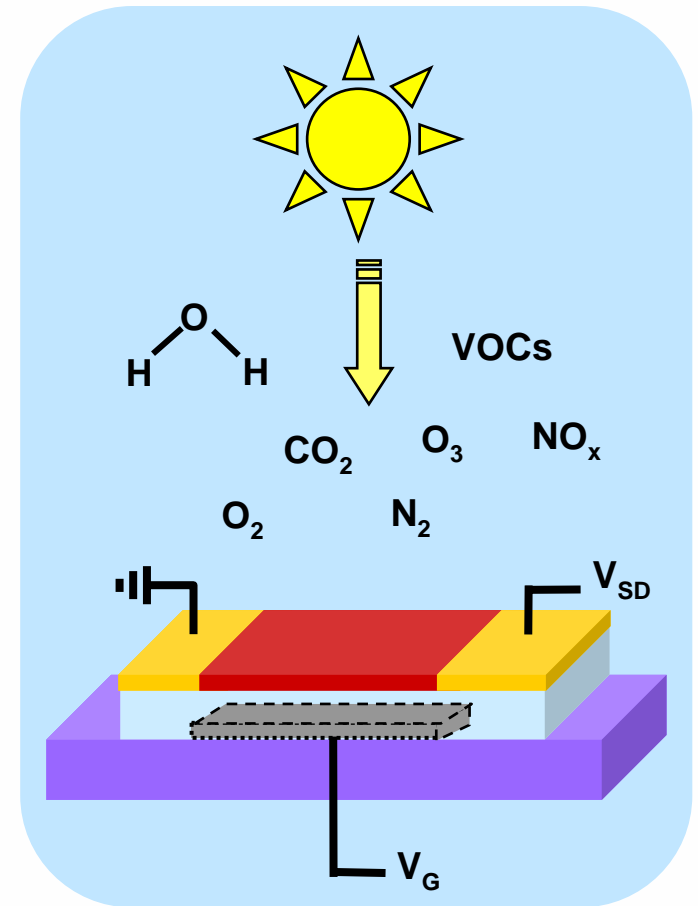
# Environmental Stability

- Photo-induced effects
  - photocurrent under operation
  - photooxidation from  $^1\text{O}_2$

*light shielding solves most problems*

- Impurities
  - contamination during fabrication
  - adsorption from the environment

*difficult to control;  
unknown effects for long-term stability*

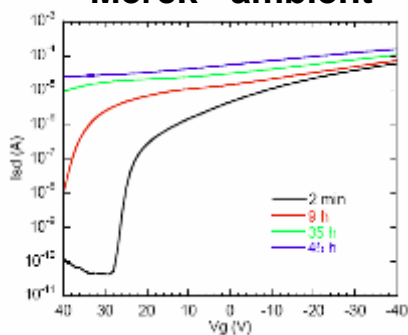




# Doping in the Ambient

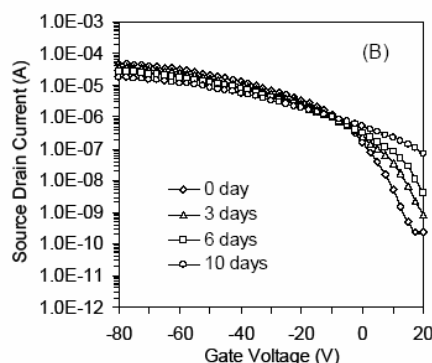
**“well-known that P3HT is doped by oxygen exposure”**

**Merck - ambient**



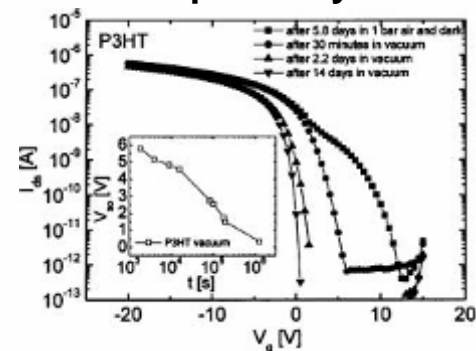
M. Heeney, et. al. *J. Am. Chem. Soc.*; **2005**

**XRCC – ambient**



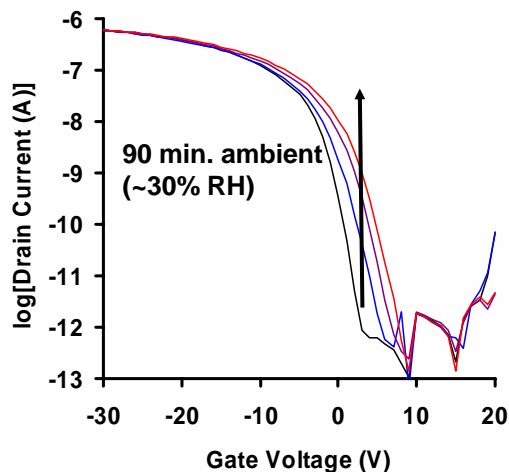
B.S. Ong, et. al. *J. Am. Chem. Soc.*; **2004**

**Philips – “dry air”**

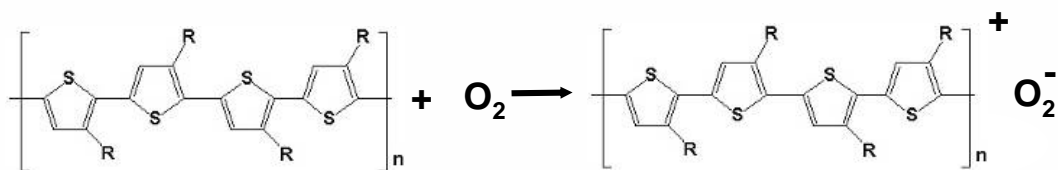


E. Meijer, et. al. *J. Appl. Phys.* 2003

**PARC – PQT-12 in ambient**



**charge transfer complex known for P3HT**



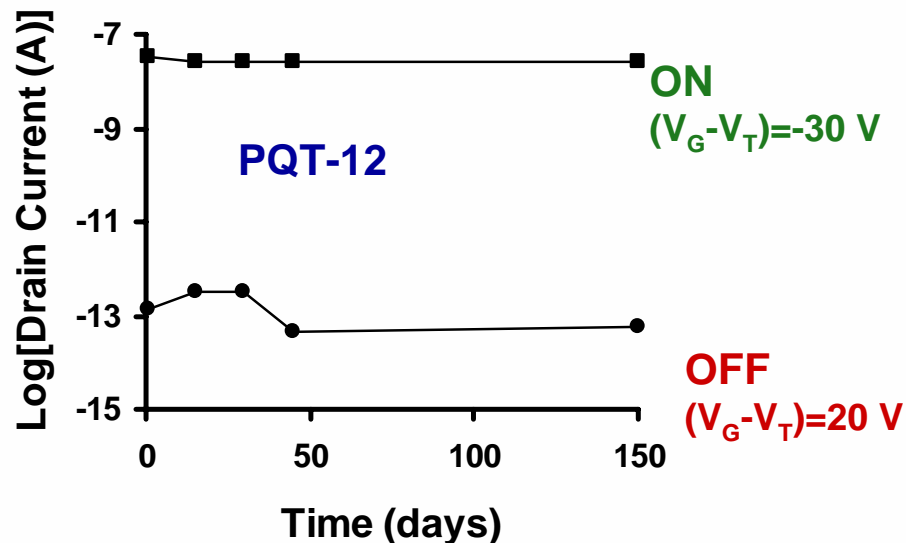
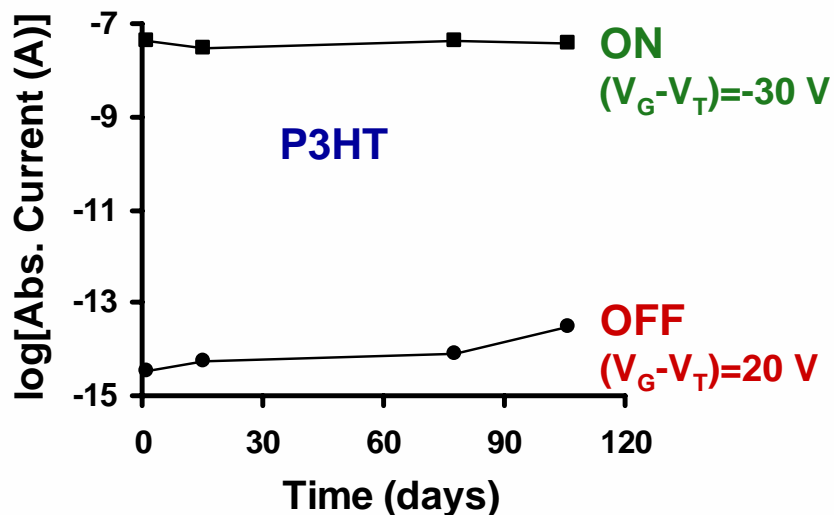
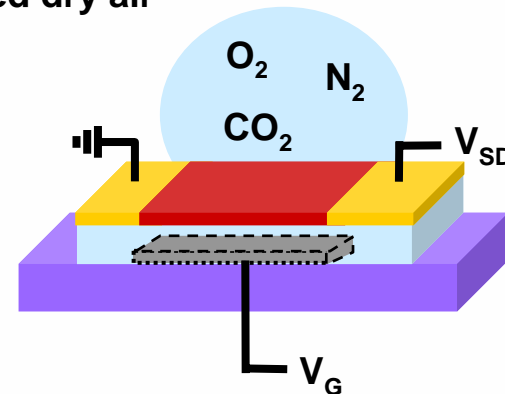
$$\Delta G \sim -0.02 \text{ eV}$$

**solubility of O<sub>2</sub> in P3HT at  
atmospheric conc. ~0.2 % volume  
Abdou, Holdcroft *JACS* 1997**

# TFT operation in clean dry air

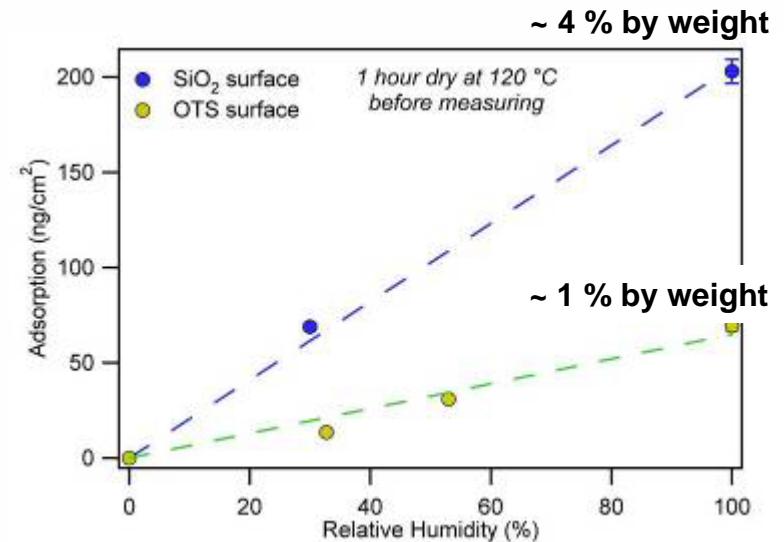
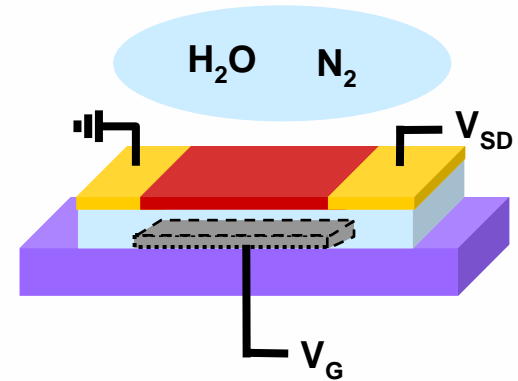
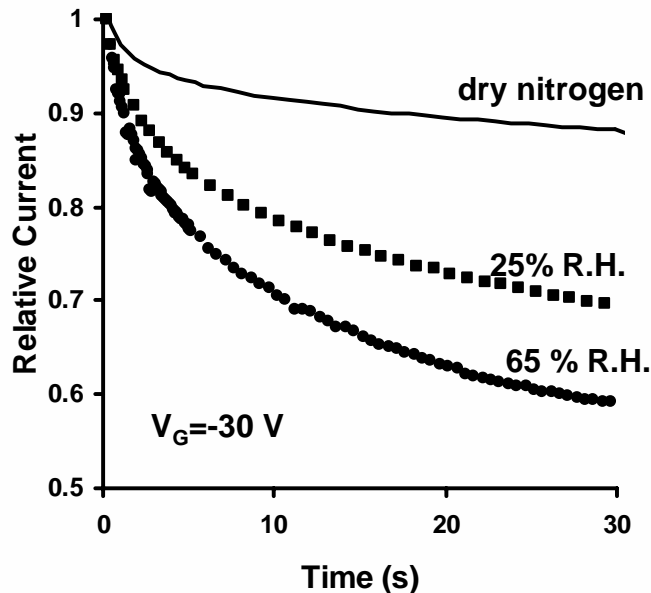
- Oxygen is evidently not a strong dopant for polythiophenes
- Air effect must be impurities

“purified dry air”



# TFT operation in the water vapor

- Mobility is relatively unaffected
- Bias stress effect is enhanced



at 30% R.H.  
 $\sim 20\text{ ng}/\text{cm}^2$  water for  
 $\sim 50\text{ nm}$  thick PQT-12 film ( $5000\text{ ng}/\text{cm}^2$ )

so  $\sim 1 \times 10^{13}\text{ H}_2\text{O}/\text{cm}^2$  in  $1\text{ nm}$   
 at  $V_G = -30\text{ V}$ ,  $C \sim 30\text{ nF}/\text{cm}^2$ ,  $\sim 5 \times 10^{12}\text{ holes}/\text{cm}^2$

$\frac{\text{H}_2\text{O molecules}}{\text{holes}} \sim 2-5$

# Some questions

- What is the structure at different length scales?
- Why does a SAM improve the a TFT?
- What is the role of surface roughness?
- Can we model the transport accurately
- How would you design a polymer to have a higher mobility?
- What is the mechanism of bias-stress; does it depend on film contamination?
- What ambient impurities are affecting the TFT and how can they be prevented?